



Product Change Notification / KSRA-16XDWZ131

Date:

23-Feb-2021

Product Category:

Memory

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4198.002 Final Notice: Qualification of ASSH as a new assembly site for selected 25AA640xx and 25LC640xx device families of 36K wafer technology available in 8L TSSOP package.

Affected CPNs:

[KSRA-16XDWZ131_Affected_CPN_02232021.pdf](#)
[KSRA-16XDWZ131_Affected_CPN_02232021.csv](#)

Notification Text:

PCN Status: Final notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change: Qualification of ASSH as a new assembly site for selected 25AA640xx and 25LC640xx device families of 36K wafer technology available in 8L TSSOP package.

Pre Change:

Assembled at ANAP using gold (Au) bond wire, 8290 die attach material, G700A molding compound material, with Matte tin lead plating finish and using lead frame without lead lock

Assembled at UNIS using gold (Au) bond wire, 8290 die attach material, G600 molding compound material, with Matte tin lead plating finish and using lead frame without lead lock

Assembled at NSEB using gold (Au) bond wire, 2200D die attach material, G600 molding compound material, with Matte tin

lead plating finish and using lead frame with lead lock

Assembled at MMT using gold (Au) bond wire, 2200D die attach material, G600V molding compound material, with Matte tin lead plating finish and using lead frame without lead lock

Post Change:Assembled at ANAP using gold (Au) bond wire, 8290 die attach material, G700A molding compound material, with Matte tin lead plating finish and using lead frame without lead lock

Assembled at UNIS using gold (Au) bond wire, 8290 die attach material, G600 molding compound material, with Matte tin lead plating finish and using lead frame without lead lock

Assembled at NSEB using gold (Au) bond wire, 2200D die attach material, G600 molding compound material, with Matte tin lead plating finish and using lead frame with lead lock

Assembled at MMT using gold (Au) bond wire, 2200D die attach material, G600V molding compound material, with Matte tin lead plating finish and using lead frame without lead lock

Assembled at ASSH using palladium coated copper (PdCu) bond wire, EN-4900GC die attach material, G700LY molding compound material, with PPF lead plating finish and using lead frame with lead lock

Pre and Post Change Summary:

	Pre Change				Post Change				
Assembly Site	Amkor Technology Philippine (P1/P2), INC. / ANAP	Unisem (M) Berhad Perak, Malaysia / UNIS	UTAC Thai Limited (UTL-1) LTD. / NSEB	Microchip Technology Thailand / MMT	Amkor Technology Philippine (P1/P2), INC. / ANAP	Unisem (M) Berhad Perak, Malaysia / UNIS	UTAC Thai Limited (UTL-1) LTD. / NSEB	Microchip Technology Thailand / MMT	ASE Advanced Semiconductor (Shanghai) Co., Ltd / ASSH
Wire material	Au	Au	Au	Au	Au	Au	Au	Au	PdCu
Die attach material	8290	8290	2200D	2200D	8290	8290	2200D	2200D	EN-4900GC
Molding compound material	G700A	G600	G600	G600V	G700A	G600	G600	G600V	G700LY
Lead frame material	C7025	C7025	C7025	C7025	C7025	C7025	C7025	C7025	C7025
Lead Plating Finish	Matte tin	Matte tin	Matte tin	Matte tin	Matte tin	Matte tin	Matte tin	Matte tin	PPF
Lead frame lead-lock	See Pre and Post Change attachment for lead frame comparison.								

Impacts to Data Sheet: None

Change Impact:None

Reason for Change:To improve on-time delivery performance by qualifying ASSH as a new assembly site.

Change Implementation Status:In Progress

Estimated First Ship Date:

March 23, 2021 (date code: 2113)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	February 2021				March 2021				
Workweek	06	07	08	09	10	11	12	13	14
Qual Report Availability			X						
Final PCN Issue Date			X						
Estimated Implementation Date								X	

Method to Identify Change: Traceability code

Qualification Report Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:**February 23, 2021:** Issued final notification. Attached the Qualification Report. Provided estimated first ship date to be on March 23, 2021

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_KSRA-16XDWZ131_Pre and Post Change Summary.pdf](#)

[PCN_KSRA-16XDWZ131_Qual_Report.pdf](#)

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

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If you wish to change your PCN profile, including opt out, please go to the **PCN home page** select login

and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

25AA640A-E/ST

25AA640A-I/ST

25AA640AT-E/ST

25AA640AT-I/ST

25LC640A-E/ST

25LC640A-I/ST

25LC640AT-E/ST

25LC640AT-I/ST

CCB 4198.002
Pre and Post Change Summary
PCN #: KSRA-16XDWZ131



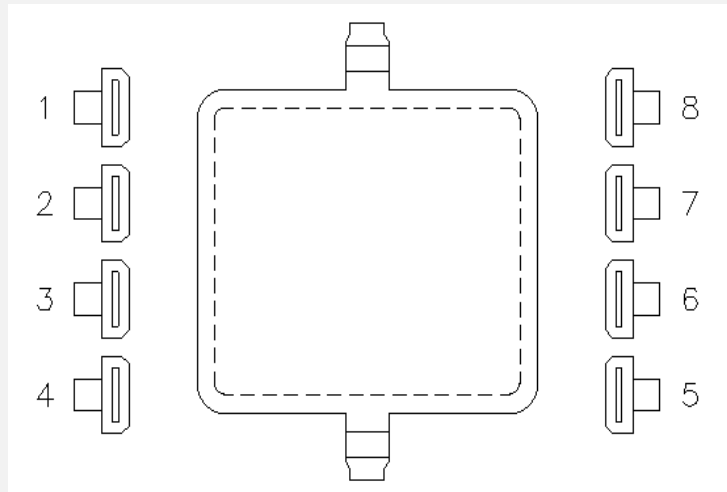
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



SMART | CONNECTED | SECURE

Lead frame comparison

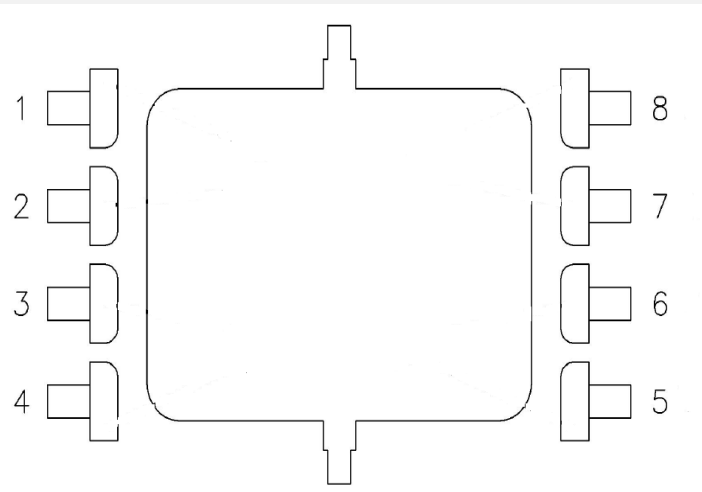
ANAP



Lead frame lead-lock

No

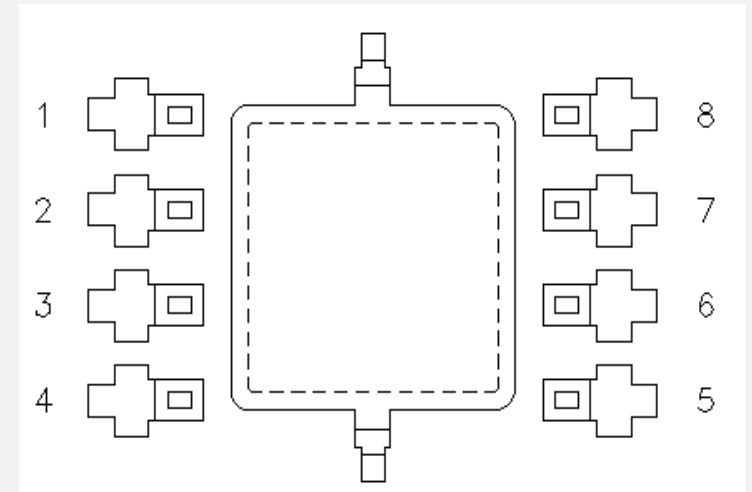
UNIS



Lead frame lead-lock

No

NSEB

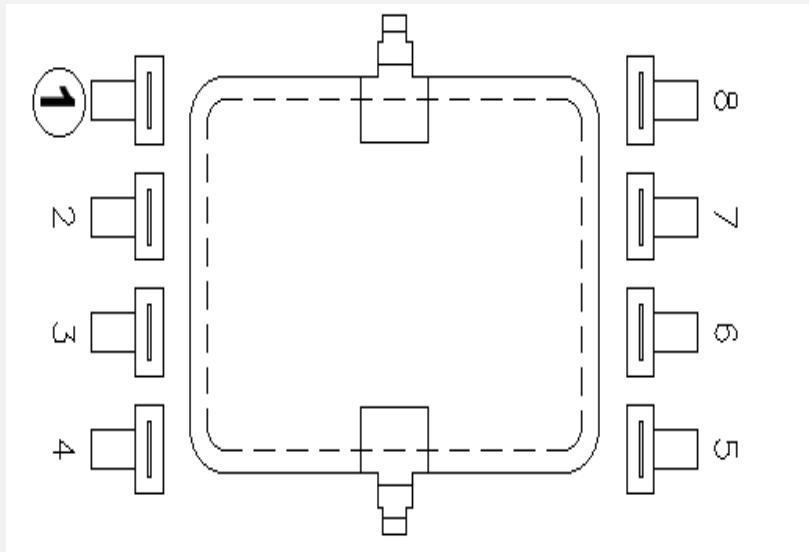


Lead frame lead-lock

Yes

Lead frame comparison

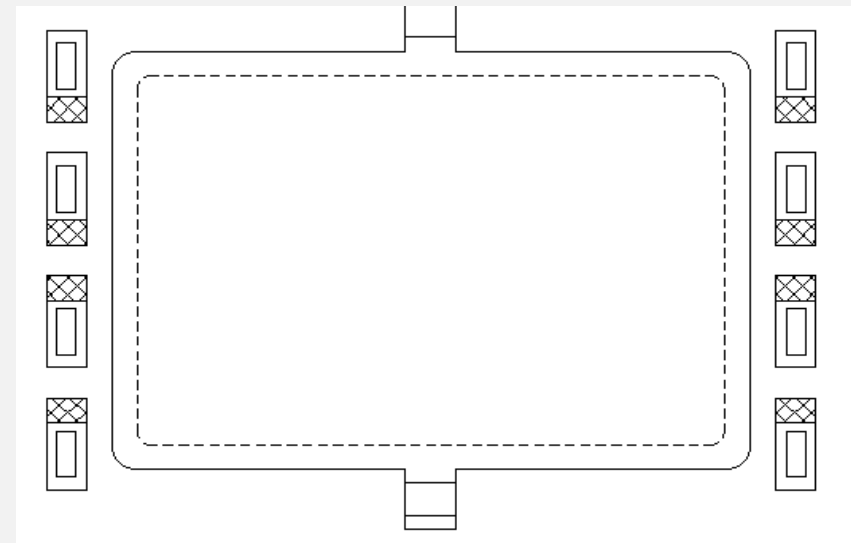
MMT



Lead frame lead-lock

No

ASSH



Lead frame lead-lock

Yes



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QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN#: KSRA-16XDWZ131

Date

October 30, 2020

**Qualification of ASSH as a new assembly site for selected
25AA640xx and 25LC640xx device families of 36K wafer
technology available in 8L TSSOP package.**



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PACKAGE QUALIFICATION REPORT

Purpose	Qualification of ASSH as a new assembly site for selected 25AA640xx and 25LC640xx device families of 36K wafer technology available in 8L TSSOP package.
CN	ES345370
CCB No	4198.002
QUAL ID	R2000526 Rev A
MP CODE	3583079CXC03
Part No.	AT24C256C-XHL-B
Bonding No.	W35830ayu
<u>Package</u>	
Type	8L TSSOP
Package size	4.4 mm
<u>Lead Frame</u>	
Paddle size	2.21 x 3.2 mils
Material	C7025
Surface	Ru-PPF
Process	Stamped
Lead Lock	Yes
Part Number	LI-WMA400008-05-00
Treatment	Roughened
<u>Material</u>	
Epoxy	EN-4900GC
Wire	PdCu
Mold Compound	G700LY
Plating Composition	Ru-PPF



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
ASSH184000082.000	MCSO518384144.000	1752USC
ASSH204400040.000	MCSO520177622.000	20057CC
ASSH204700076.000	MCSO520167575.000	2008CDJ

Result

Pass Fail _____

8L TSSOP assembled by ASSH pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020E)	IPC/JEDEC J-STD-020E	135	0/135	Pass	
Precondition Prior Perform Reliability Tests (At MSL Level 1)	Electrical Test: +25°C, 85°C and 125°C System: NEXTEST_PT Bake 150°C, 24 hrs System: CHINEE 85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 Electrical Test: +25°C, 85°C and 125°C System: NEXTEST_PT	JESD22-A113	693(0)	693 693 693 0/693	 Pass	Good Devices
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +85°C and 125°C System: NEXTEST_PT Bond Strength: Wire Pull (>4.00 grams) Bond Shear (>18.00 grams)	JESD22-A104	 231(0) 45 (0)	231 0/231 0/45	 Pass Pass	Parts had been pre-conditioned at 260°C
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 5.5 Volts System: HAST 6000X Electrical Test: +25°C, 85°C and 125°C System: NEXTEST_PT Bond Strength: Wire Pull (>4.00 grams) Bond Shear (>18.00 grams)	JESD22-A110	 231(0) 45 (0)	231 0/231 0/45	 Pass Pass	Parts had been pre-conditioned at 260°C 77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: NEXTEST_PT		231(0)	0/231	Pass	77 units / lot
High Temperature Storage Life	Stress Condition: Bake 175°C, 500 hrs System: TPS DC-166-F-ST350	JESD22-A103		135		45 units / lot
	Electrical Test: +25°C, 85°C and 125°C System: NEXTEST_PT		135(0)	0/135	Pass	
Solderability Temp 215°C	Steam Aging: Temp 93°C,8Hrs System: SAS-3000 Solder Dipping: Solder Temp.215°C Solder material: SnPb Sn63, Pb37 System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22 (0)	22		
				22	0/22	Pass
Solderability Temp 245°C	Steam Aging: Temp 93°C,8Hrs System: SAS-3000 Solder Dipping:Solder Temp.245°C Solder material:Pb Free Sn 95.5Ag3.9 Cu0.6 System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22 (0)	22		
				22	0/22	Pass
Bond Strength Data Assembly	Wire Pull (> - grams)	Mil.Std. 883-2011	30 (0)	-	-	
	Bond Shear (> - grams)	CDF-AEC-Q100-001	30 (0)	-	-	